

## **Recent publications from the NIST in the fields of AUV**

B.F. Payne, K. K. Harper, and G. W. Vogl, Piezoelectric Shaker Development for High Frequency Calibration of Accelerometers. Proceedings: 9th International Conference on Vibration Measurements by Laser and Non-contact Techniques, Ancona, 373 – 383 (2010)  
[http://www.nist.gov/customcf/get\\_pdf.cfm?pub\\_id=905194](http://www.nist.gov/customcf/get_pdf.cfm?pub_id=905194)

G. W. Vogl, K. K. Harper, and B. F. Payne, Modeling and Experimental Analysis of Piezoelectric Shakers for High-Frequency Calibration of Accelerometers. Proceedings: 9th International Conference on Vibration Measurements by Laser and Non-contact Techniques, Ancona, 383 – 393 (2010)  
[http://www.nist.gov/customcf/get\\_pdf.cfm?pub\\_id=905341](http://www.nist.gov/customcf/get_pdf.cfm?pub_id=905341)

D. J. Evans and H. C. Pussey, Chapter 17 Shock and Vibration Standards. Harris' Shock and Vibration Handbook, Sixth Edition, McGraw-Hill, New York, NY, 17.1 - 17.8 (2010)

D. J. Evans, A. Hornikova, S. D. Leigh, A. L. Rukhin, and W. Strawderman, Report on Acceleration Comparison SIM.AUV.V-K1. Metrologia **46**, (2009), Tech. Suppl., 09002  
[http://www.bipm.org/utils/common/pdf/final\\_reports/AUV/V-K1/SIM.AUV.V-K1.pdf](http://www.bipm.org/utils/common/pdf/final_reports/AUV/V-K1/SIM.AUV.V-K1.pdf)

R. P. Wagner and V. Nedzelnitsky, Determination of Wave Motion Correction Values Required for Comparison Calibrations of a New Working Standard Microphone. NIST Interagency/Internal Report (NISTIR) – 7526, 1 – 13 (2008)  
[http://www.nist.gov/customcf/get\\_pdf.cfm?pub\\_id=824744](http://www.nist.gov/customcf/get_pdf.cfm?pub_id=824744)

S. E. Fick, Long-term Stability of the NIST Standard Ultrasonic Source, J. Res. Natl. Inst. Stand. Technol. **113**, 281-286 (2008)  
[http://www.nist.gov/customcf/get\\_pdf.cfm?pub\\_id=824662](http://www.nist.gov/customcf/get_pdf.cfm?pub_id=824662)

V. Nedzelnitsky and R. P. Wagner, Non-Contact Methods for Measuring Front Cavity Depths of Laboratory Standard Microphones Using a Depth-Measuring Microscope. J. Res. Natl. Inst. Stand. Technol. **113**, 97-119 (2008)  
<http://nvl.nist.gov/pub/nistpubs/jres/113/2/V113.N02.A03.pdf>

R. P. Wagner and V. Nedzelnitsky, Effect of Power Line Interference on Microphone Calibration Measurements Made at or Near Harmonics of the Power Line Frequency, J. Res. Natl. Inst. Stand. Technol. **112**, 107-114 (2007)  
<http://nvl.nist.gov/pub/nistpubs/jres/112/2/V112.N02.A03.pdf>

S. E. Fick and D. Ruggles, In-situ Attenuation Corrections for Radiation Force Measurements of High Frequency Ultrasound With a Conical Target, J. Res. Natl. Inst. Stand. Technol. **111**, 435-442 (2006)  
<http://nvl.nist.gov/pub/nistpubs/jres/111/6/V111.N06.A04.pdf>